

Application Data Sheet

No. 170

System Gas Chromatograph

Impurities in p-Xylene Analysis Nexis GC-2030PXY1 GC-2014PXY1

This method is for determining trace impurities in xylene as described in below compound table. It requires the use of a dedicated gas chromatographic system which is configured with an automatic liquid injector.

Analyzer Information

System Configuration:

One SPL injector / one capillary column / one FID

Sample Information:

Determining impurities in p-xylene

Methods met:

ASTM-D3798

Concentration Range:

No.	Name of Compound	Concentration Range	
		Low Conc.	High Conc.
1	Non aromatics	10 ppmwt	10,000 ppmwt
2	Toluene	10 ppmwt	10,000 ppmwt
3	Ethylbenzene	10 ppmwt	10,000 ppmwt
4	p-Xylene	99 %wt	100 %wt
5	m-Xylene	10 ppmwt	10,000 ppmwt
6	Benzene	10 ppmwt	10,000 ppmwt
7	Isopropylbenzene	10 ppmwt	10,000 ppmwt
8	o-Xylene	10 ppmwt	10,000 ppmwt

Detection limits may vary depending on the sample.
Please contact us for more consultation.

System Features

- Single FID channel
- Good repeatability

Typical Chromatograms

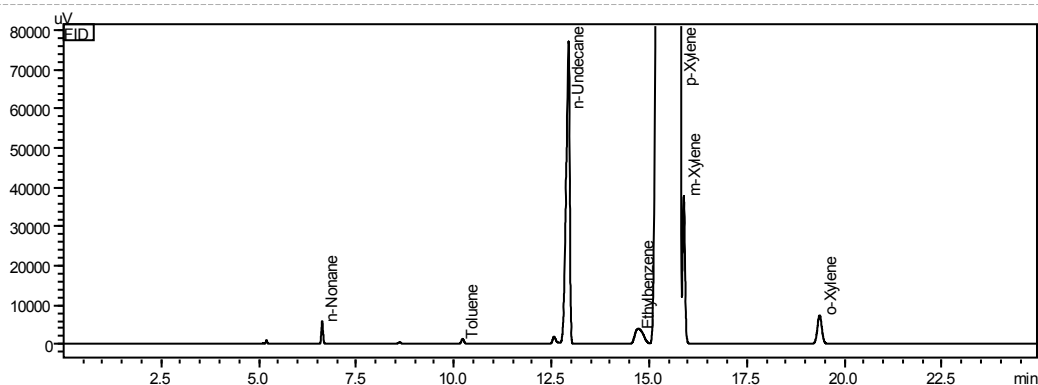


Fig. 1 Chromatogram of FID

First Edition: November, 2017